

GENE-HD05

PCB Rev. A0.2

Temperature/Humidity Test Report

Report NO:

Summary	<p><input checked="" type="checkbox"/> Pass <input type="checkbox"/> Fail</p> <p>Note : There is/are ____ defect(s) not list in the report, please check it in the DTS Website.</p> <p><input type="checkbox"/> Pass with Deviation</p>
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Issue date

2012-06-07

Approval

Benson Lee

Test Engineer

Yung Tang Lin

Test item list

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Testing Result

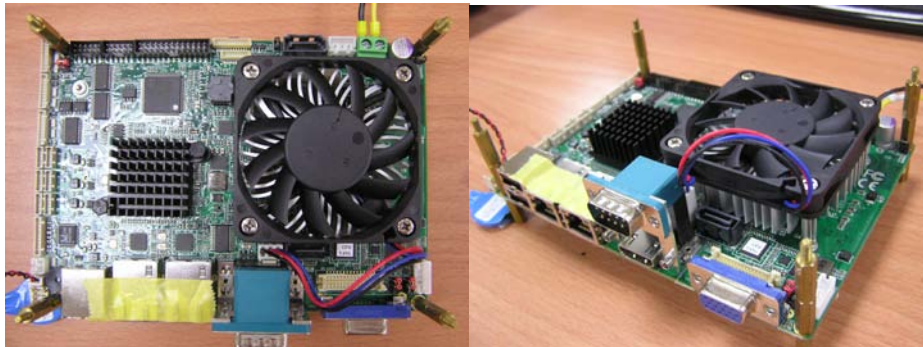
Num	Test item list	Result	Remark
1	Temp./humidity power on/off test	Pass	N/A
2	Temperature variation operation test	Pass	N/A
3	Cold start and hot start test	Pass	N/A

Configuration of EUT

Test Product: GENE-HD05 A0.2

Sample Configuration & Quantity Under Test:

1. **CPU:** AMD G-series T56N (1.65GHz Dual Core)
2. **Chipset:** G-Series A50M Chipset
3. **VGA:** AMD Radeon HD 6320
4. **Memory:** Transecnd 2GB DDR3 1066 SODIMM CL7
5. **BIOS Reversion:** GHD5AM05
6. **CFast:** N/A
7. **SATA HDD:** HITACHI 320GB MLC
8. Test Software: Windows 7 x64 with SP1/ Run PassMark BurnInTest Pro v7.0 build 1004
9. Power Supply: EMACS HG2-6400P (ATX-Mode)
10. Cooler:



Temp./humidity power on/off test

Test Date: 2012-05-31--06-01

Test Site: AAEON Taichung Internal Lab

Test Standard: Reference IEC 68-2-30 Testing procedures
Test Db: Damp Heat Test

Test Equipment:

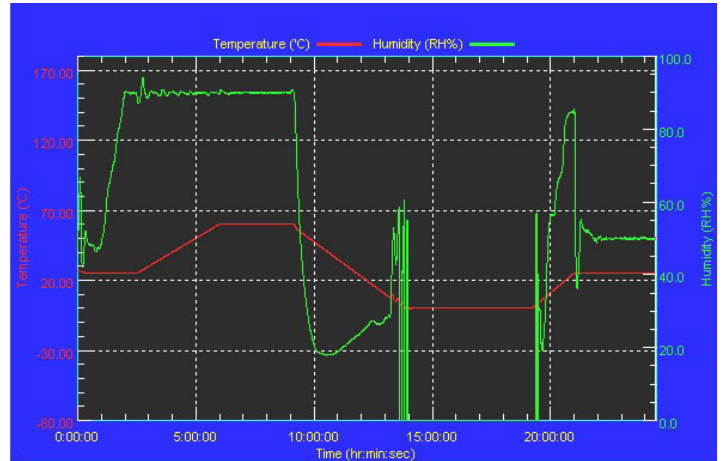
Programmable Temperature & Humidity Chamber
TERCHY. TECH. CORP.
Model: MHU-150LB
Date of Calibration: 2012/03/07
Serial Number: 961138

Temperature & Humidity Power On/Off Test:

Testing Specification:

Step	Temperature (°C)	Humidity (%RH)	Duration (HH:MM)
1	25	50	00:30
2	25	50	00:30
3	25	90	01:00
4	25	90	00:30
5	60	90	03:30
6	60	90	03:00
7	0	0	04:50
8	0	0	05:23
9	25	50	01:47
10	25	50	03:00

Test Curve:



Test Result:

No problem was found during the temperature & humidity power on/off test.

Test Method	Actual	Successful	Failure rate
Power On/Off	1587/ times	1585/ times	0.1 %
Note: Failure rate need to under 0.2%.			

Temperature variation operation test

Test Date: 2012-06-04~06-05

Test Site: AAEON Taichung Internal Lab

Test Standard: Reference IEC 68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

Programmable Temperature & Humidity Chamber

TERCHY. TECH. CORP.

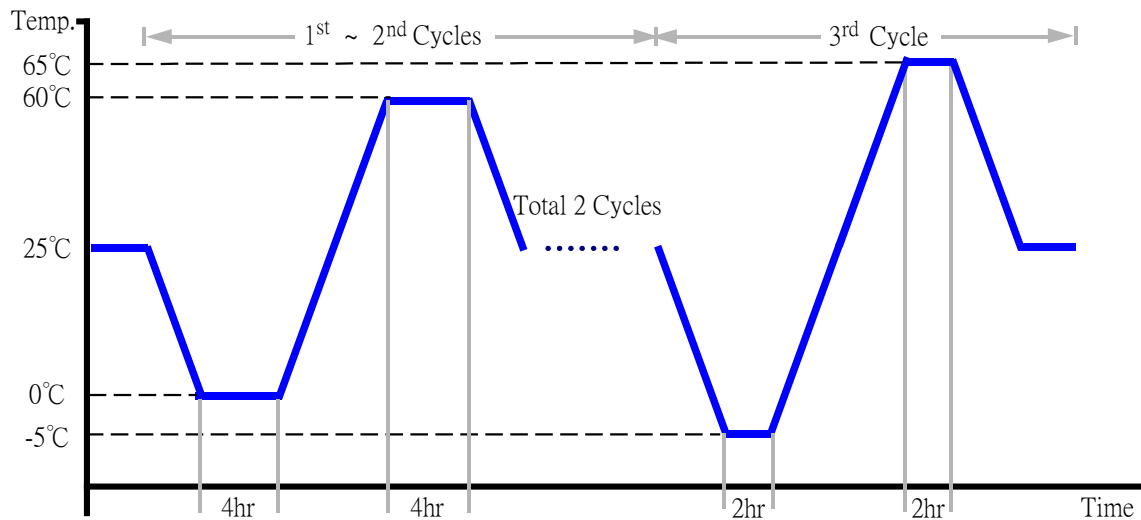
Model: MHU-150LB

Date of Calibration: 2012/03/07

Serial Number: 961138

Temperature & Humidity Cycle Test:

1. Test Low Temperature: **0°C** (1st~2nd cycles)
-5°C (3rd cycle)
2. Test High Temperature: **60°C** (1st~2nd cycles)
65°C (3rd cycle)
3. Test dwell time: **4Hrs** (1st~2nd cycles)
2Hrs (3rd cycle)
4. Temperature slope: **2°C/min**
5. Test cycle: **3 cycles**
6. Test Environment Curve:



Test Result:

No problem was found during the temperature variation operation test.

Cold start and hot start test

Test Date: 2012-06-06

Test Site: AAEON Taichung Internal Lab

Test Standard: Reference IEC 68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

Programmable Temperature & Humidity Chamber

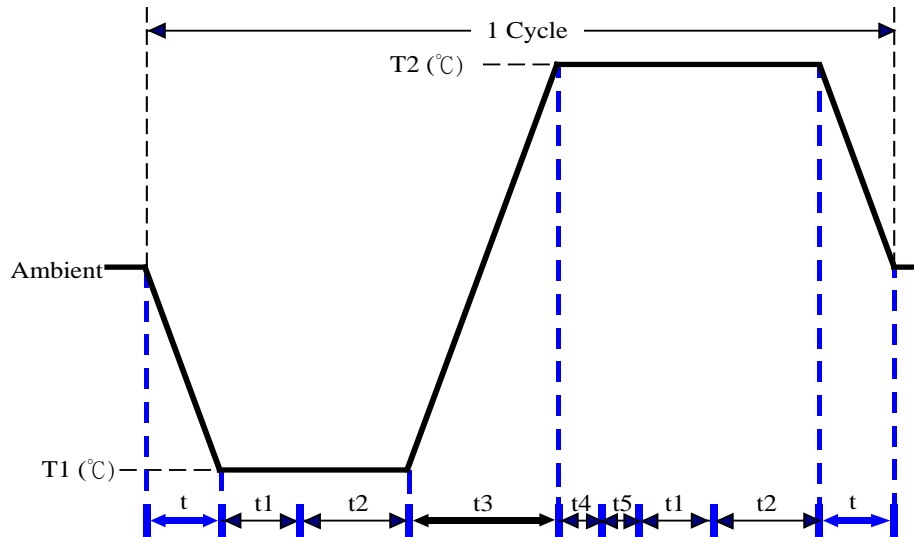
TERCHY. TECH. CORP.

Model: MHU-150LB

Date of Calibration: 2012/03/07

Serial Number: 961138

Test Condition:



Parameters	Description
T_1	-5°C
T_2	65°C
t_1	1 hr
t_2	2 hrs
t_4, t_5	30 mins
t, t_3	2°C/min
n (Cycle)	1

t, t_3 : Temperature Slope

t, t_1 : Power Off

t_2 : Power On/Off test 10 times (On 2 mins / Off 5 mins)

t_5 : Windows soft restart test 2 times

Test software: Windows 7 Ultimate x64 Edition

Test Result:

- No problem was found during the cold start test.
- No problem was found during the hot start test.